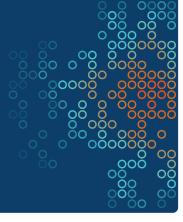


Optical Sensing Analyzer | si730



Applications

- Measurements of fiber bragg grating (FBG) strain gages, temperature probes, accelerometers, pressure sensors and other FBG sensors.
- Simultaneous dynamic and static measurements of hundreds of sensors.
- Permanent installations for tracking the condition and performance in smart structures like bridges, dams, buildings and tunnels.
- Continuous, decades-long, structural health monitoring of ships, aircraft, trains and other complex structures.

Features

- More sensors Wide range swept laser scanning means more sensors per channel (4x the competition).
- More channels Up to 16 channels can be built into the si730 package.
- · Fast dynamic measurements.
- Spectral Diagnotic View Observe sensor optical characteristics during setup.

Description

The Micron Optics si730 is a convenient, full-featured, optical sensing instrument that provides simultaneous static and dynamic interrogation of hundreds of fiber optic sensors. Its large touchscreen and built in ENLIGHT^{Pro} graphical user interface make it ideal for laboratory use. The combination of high speed and repeatability of the swept wavelength laser-based system allows a single instrument to interrogate dynamic sensors and measure static sensors with ultra-high resolution.

The "si" in the Micron Optics si730 interrogator name indicates that it is a "Sensing Instrument" (not an "sm", or "Sensing Module"). The si platform uses an MOI optimized integrated ENLIGHT^{Pro} environment built upon Windows XP Embedded technology. This facilitates on-board management of all x30 optical core settings, data acquisition, sensor calibration, data visualization, and data storage. Users of Integrated ENLIGHT^{Pro} interface to the si through a touchscreen LCD, external keyboard/mouse/monitor, or Windows Remote Desktop connections.



si730 Laboratory Instrument

ENLIGHT^{Pro} Sensing Analysis Software is included with Micron Optics sensing interrogator systems and provides a single suite of tools for data acquisition, computation, and analysis of optical sensor networks. ENLIGHT^{Pro} combines the useful features of traditional sensor software with the specific needs of the optical sensor system, making it easy to optimize optical properties during the design and implementation phase of an optical sensor system. Intuitive data display and additional graphing and data visualization features make ENLIGHT^{Pro} easy to use. Learn more about ENLIGHT^{Pro} at: http://www.micronoptics.com/sensing_software.php.

Optical Sensing Analyzer | si730



Specifications (B)	si730-500	si730-800	
Optical Properties			
Number of Optical Channels	4	16	
Scan Frequency	1kHz	250 Hz	
Wavelength Range	1510-1590 nm		
Wavelength Stability ²	2 pm typ, 5 pm max		
Wavelength Repeatability ³	1 pm, 0.05 pm with 1,000 averages		
Dynamic Range ⁴	25 dB with user-selectable gain		
Max FBGs per Channel	80 (up to 160 with expanded λ range)		
Internal Peak Detection	Included		
Spectral Diagnostic View	Included		
Optical Connectors	FC/APC		
FBG Requirements 5	0.25 +/- 0.05nm, FWHM (-3dB point); >15dB Isolation		

Data	Processing	Capa	bilities

Operating Environment	Integrated MOI ENLIGHT Environment (based on XP Embedded)	
Enhanced Data Management	ENLIGHT ^{Pro} Sensing Analysis Software	
Interfaces	USB 2.0, Ethernet, 17" Touchscreen LCD	
Storage Capacity	100 GB HDD	
Ethernet Pass-through	Supports direct data acquisition from Optical Sensing Interrogator Core	

Mechanical, Environmental, Electrical Properties

Dimensions; Weight	520 mm x 499 mm x 165 mm; 18.1 kg (40 lbs)
Operating Temperature; Humidity	10° to 35°C; 20 to 80%, non-condensing
Storage Temperature; Humidity	-20° to 60°C; 5 to 95%, non-condensing
Input Voltage	7 - 36 VDC (100~240 VAC, 47~63Hz), AC/DC converter included
Power Consumption at 12V	65 W typ, 80 max

Notes:

- $1. \ \ Beta\ product. For\ details\ see\ \underline{www.micronoptics.com/product_designation.php.}$
- $2. \ \ Captures \ effects \ of long \ term \ use \ over full \ operating \ temperature \ range \ of \ the \ instrument. \ (Assumes \ an FBG \ bandwidth \ of \ 0.25nm).$
- $3. \ Per \ NIST \ Technical \ Note \ 1297, 1994 \ Edition, Section \ D.1.1.2, definition \ of "repeatability \ [of results of measurements]". (Assumes an FBG bandwidth of 0.25nm).$
- 4. Defined as laser launch power minus detection noise floor. Adjustable 13 dB window within total range.
- $5. \ \ Used for performance \ qualification \ (See \ Notes \ 2 \ and \ 3). \ \ Bandwidths \ of \ 0.1 \ to \ 1.0 nm \ may \ reduce \ performance.$



